

**University of New Mexico**  
**Department of Electrical and Computer Engineering**

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**ECE 520 - VLSI Design (spring 2026)**

**Homework #1**

*Due in class: Thursday Jan. 29, 2026*

1. In order to estimate the fabrication cost, we need to determine the number of dies in a wafer. Prove the equations in slide 61 of Lecture 1. Then, use the equations in the slide to determine the percentage of wasted silicon (due to the edge of the wafer), as a function of die size. Plot the % wasted area as a function of die size for die sizes from 1 Cm to 5 Cm in an 8-inch wafer.
  
2. In this problem, we would like to derive the equation for drain current in saturation region considering channel-length modulation. Assume that the change in channel length is proportional to  $V_{DS}$  (i.e.,  $\Delta L/L = \lambda V_{DS}$ ). Show how equation (3.29) in your textbook becomes (3.30) when you include channel length modulation.
  
3. Based on the list of previous VLSI projects for ECE520/424 that we discussed in Lecture 1, please suggest at least one new project that you will be interested in designing and working on during this semester. Please explain how you design your suggested project. Feel free to use any online resources.